

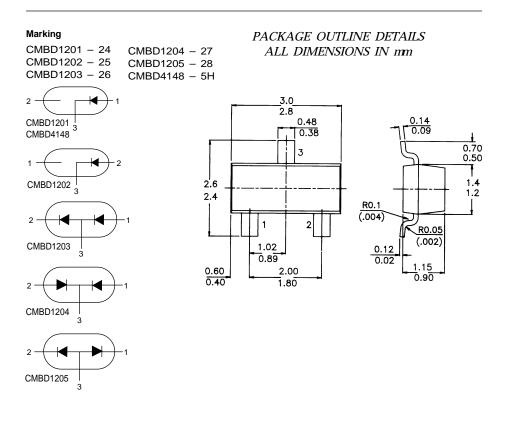


SOT-23 Formed SMD Package

CMBD1201, CMBD1202, CMBD1203 CMBD1204, CMBD1205, CMBD4148

SILICON PLANAR EPITAXIAL HIGH SPEED DIODES

CMBD1201, 1202, CMBD4148 are all single diodes CMBD1203 is a dual diode, in series CMBD1204 is a dual diode, common cathode CMBD1205 is a dual diode, common anode



ABSOLUTE MAXIMUM RATINGS (per diode)

Continuous reverse voltage	V_R	max.	75 V
Repetitive peak reverse voltage	V _{RRM}	max.	100 V
Repetitive peak forward current	I _{FRM}	max.	500 mA
Forward current	I_F	max.	215 mA
Junction temperature	T_{j}	max.	150 °C
Forward voltage at $I_F = 10 mA$	\check{V}_F	<	0.855 V

CMBD1201, CMBD1202, CMBD1203 CMBD1204, CMBD1205, CMBD4148

Reverse recovery time when switched from					
$I_F = 10 \ mA$ to $I_R = 10 \ mA$; $R_L = 100 \ \Omega$;					
measured at $I_R = 1 mA$	t _{rr}	<	4 ns		
RATINGS (per diode) (at $T_A = 25^{\circ}C$ unless otherwise specified)					
Limiting values					
Continuous reverse voltage	V_R	max.	75 V		
Repetitive peak reverse voltage	V_{RRM}	max.	100 V		
Repetitive peak forward current	I _{FRM}	max.	500 mA		
Forward current	I_F	max.	215 mA		
Non-repetitive peak forward current (per crystal)					
$t = 1 \ \mu s$	IFSM	max.	4 A		
t = 1 ms	IFSM	max.	1.0 A		
t = 1 s	IFSM	max.	0.5 A		
Storage temperature	Tstg	–55 te	o +150 °C		
Junction temperature	Τj	max.	150 °C		
THERMAL RESISTANCE					
From junction to ambient	R _{th j-a}	=	500 K/W		
	U				
CHARACTERISTICS (per diode)					
$T_i = 25$ °C unless otherwise specified					
Forward voltage					
$I_F = 10 mA$	V_F	<	0.855 V		
$I_F = 200 \ mA$	V_F	<	1.05 V		
$I_F = 10 mA$ CMBD4148	V_F	<	1.0 V		
Reverse currents					
$V_R = 20 V$	I_R	<	25 nA		
$V_R = 75 V$	I_R	<	5 μA		
$V_R = 25 V; T_j = 150 \ ^{\circ}C$	I_R	<	30 μA		
-	-1				
Forward recovery voltage	17		1 77 17		
$I_F = 10 \text{ mA}; t_p = 20 \text{ ns}$	V_{fr}	<	1.75 V		
Recovery charge					
$I_F = 10 \text{ mA to } V_R = 5V; R = 100 \Omega$	Q_{s}	<	45 pC		
Diode capacitance					
$V_R = 0; f = 1 MHz$	C_d	<	2 pF		
	u		1-		
Reverse recovery time when switched from $L_{T} = 10 \text{ m} \Lambda$ to $L_{T} = 10 \text{ m} \Lambda$; $R_{T} = 100 \Omega$;					
$I_F = 10 \text{ mA to } I_R = 10 \text{ mA}; R_L = 100 \Omega;$	+		1		
measured at $I_R = 1 mA$	t_{TT}	<	4 ns		

Customer Notes

Disclaimer

The product information and the selection guides facilitate selection of the CDIL's Discrete Semiconductor Device(s) best suited for application in your product(s) as per your requirement. It is recommended that you completely review our Data Sheet(s) so as to confirm that the Device(s) meet functionality parameters for your application. The information furnished on the CDIL Web Site/ CD are believed to be accurate and reliable. CDIL however, does not assume responsibility for inaccuracies or incomplete information. Furthermore, CDIL does not assume liability whatsoever, arising out of the application or use of any CDIL product; neither does it convey any license under its patent rights nor rights of others. These products are not designed for use in life saving/support appliances or systems. CDIL customers selling these products (either as individual Discrete Semiconductor Devices or incorporated in their end products), in any life saving/support appliances or systems or applications do so at their own risk and CDIL will not be responsible for any damages resulting from such sale(s).

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Data Sheet